

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/621,510	YESHURUN, YEHOSHUA
	Examiner Mark K. Han	Art Unit 3767

SEARCHED			
Class	Subclass	Date	Examiner
604	19 20	10/2/2006	mhk.
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner